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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M7
Core Size	32-Bit Single-Core
Speed	216MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I <sup>2</sup> C, IrDA, LINbus, MMC/SD/SDIO, QSPI, SAI, SPDIF, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I <sup>2</sup> S, LCD, POR, PWM, WDT
Number of I/O	159
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	512K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 24x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	216-TFBGA
Supplier Device Package	216-TFBGA (13x13)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f777nih7">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f777nih7</a>

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## 2.3 Embedded Flash memory

The STM32F777xx, STM32F778Ax and STM32F779xx devices embed a Flash memory of up to 2 Mbytes available for storing programs and data. The Flash interface features:

- Single /or Dual bank operating modes,
- Read-While-Write (RWW) in Dual bank mode.

## 2.4 CRC (cyclic redundancy check) calculation unit

The CRC (cyclic redundancy check) calculation unit is used to get a CRC code using a configurable generator polynomial value and size.

Among other applications, CRC-based techniques are used to verify data transmission or storage integrity. In the scope of the EN/IEC 60335-1 standard, they offer a means of verifying the Flash memory integrity. The CRC calculation unit helps compute a signature of the software during runtime, to be compared with a reference signature generated at link-time and stored at a given memory location.

## 2.5 Embedded SRAM

All the devices feature:

- System SRAM up to 512 Kbytes:
  - SRAM1 on AHB bus Matrix: 368 Kbytes
  - SRAM2 on AHB bus Matrix: 16 Kbytes
  - DTCM-RAM on TCM interface (Tightly Coupled Memory interface): 128 Kbytes for critical real-time data.
- Instruction RAM (ITCM-RAM) 16 Kbytes:
  - It is mapped on TCM interface and reserved only for CPU Execution/Instruction useful for critical real-time routines.

The Data TCM RAM is accessible by the GP-DMA's and peripherals DMA's through specific AHB slave of the CPU. The instruction TCM RAM is reserved only for CPU. It is accessed at CPU clock speed with 0 wait states.

- 4 Kbytes of backup SRAM
  - This area is accessible only from the CPU. Its content is protected against possible unwanted write accesses, and is retained in Standby or VBAT mode.

## 2.6 AXI-AHB bus matrix

The STM32F777xx, STM32F778Ax and STM32F779xx system architecture is based on 2 sub-systems:

- An AXI to multi AHB bridge converting AXI4 protocol to AHB-Lite protocol:
  - 3x AXI to 32-bit AHB bridges connected to AHB bus matrix
  - 1x AXI to 64-bit AHB bridge connected to the embedded Flash memory
- A multi-AHB Bus-Matrix
  - The 32-bit multi-AHB bus matrix interconnects all the masters (CPU, DMA's, Ethernet, USB HS, LCD-TFT, and DMA2D) and the slaves (Flash memory, RAM,

## 2.7 DMA controller (DMA)

The devices feature two general-purpose dual-port DMAs (DMA1 and DMA2) with 8 streams each. They are able to manage memory-to-memory, peripheral-to-memory and memory-to-peripheral transfers. They feature dedicated FIFOs for APB/AHB peripherals, support burst transfer and are designed to provide the maximum peripheral bandwidth (AHB/APB).

The two DMA controllers support circular buffer management, so that no specific code is needed when the controller reaches the end of the buffer. The two DMA controllers also have a double buffering feature, which automates the use and switching of two memory buffers without requiring any special code.

Each stream is connected to dedicated hardware DMA requests, with support for software trigger on each stream. The configuration is made by software and the transfer sizes between the source and the destination are independent.

The DMA can be used with the main peripherals:

- SPI and I<sup>2</sup>S
- I<sup>2</sup>C
- USART
- General-purpose, basic and advanced-control timers TIMx
- DAC
- SDMMC
- Cryptographic acceleration
- Camera interface (DCMI)
- ADC
- SAI
- SPDIFRX
- Quad-SPI
- HDMI-CEC
- JPEG codec
- DFSDM1

The devices embed two dedicated PLL (PLLI2S and PLLSAI) which allow to achieve audio class performance. In this case, the I<sup>2</sup>S and SAI master clock can generate all standard sampling frequencies from 8 kHz to 192 kHz.

## 2.16 Boot modes

At startup, the boot memory space is selected by the BOOT pin and BOOT\_ADDx option bytes, allowing to program any boot memory address from 0x0000 0000 to 0x3FFF FFFF which includes:

- All Flash address space mapped on ITCM or AXIM interface
- All RAM address space: ITCM, DTCM RAMs and SRAMs mapped on AXIM interface
- The System memory bootloader

The boot loader is located in system memory. It is used to reprogram the Flash memory through a serial interface. Refer to *STM32 microcontroller system memory boot mode* application note (AN2606) for details.

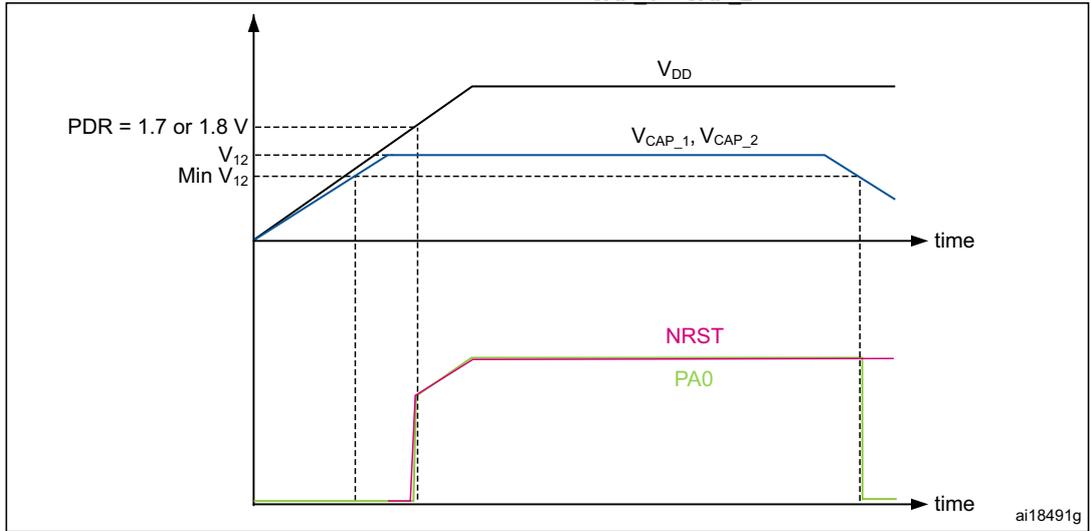
## 2.17 Power supply schemes

- $V_{DD} = 1.7$  to  $3.6$  V: external power supply for I/Os and the internal regulator (when enabled), provided externally through  $V_{DD}$  pins.
- $V_{SSA}$ ,  $V_{DDA} = 1.7$  to  $3.6$  V: external analog power supplies for ADC, DAC, Reset blocks, RCs and PLL.  $V_{DDA}$  and  $V_{SSA}$  must be connected to  $V_{DD}$  and  $V_{SS}$ , respectively.
- $V_{BAT} = 1.65$  to  $3.6$  V: power supply for RTC, external clock 32 kHz oscillator and backup registers (through power switch) when  $V_{DD}$  is not present.

*Note:*  $V_{DD}/V_{DDA}$  minimum value of 1.7 V is obtained when the internal reset is OFF (refer to Section 2.18.2: *Internal reset OFF*). Refer to Table 3: *Voltage regulator configuration mode versus device operating mode* to identify the packages supporting this option.

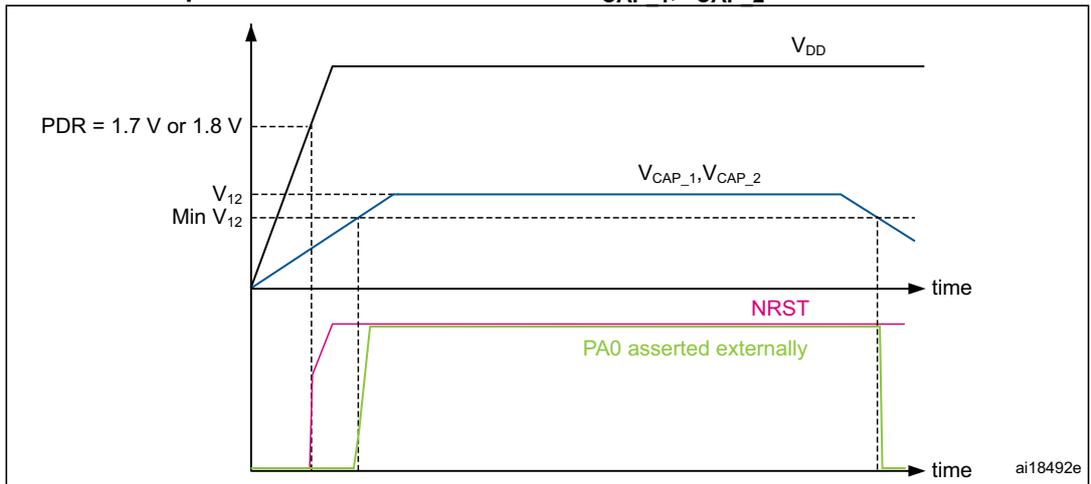
- $V_{DDSDMMC}$  can be connected either to  $V_{DD}$  or an external independent power supply (1.8 to 3.6V) for SDMMC2 pins (clock, command, and 4-bit data). For example, when the device is powered at 1.8V, an independent power supply 2.7V can be connected to  $V_{DDSDMMC}$ . When the  $V_{DDSDMMC}$  is connected to a separated power supply, it is independent from  $V_{DD}$  or  $V_{DDA}$  but it must be the last supply to be provided and the first to disappear. The following conditions  $V_{DDSDMMC}$  must be respected:
  - During the power-on phase ( $V_{DD} < V_{DD\_MIN}$ ),  $V_{DDSDMMC}$  should be always lower than  $V_{DD}$
  - During the power-down phase ( $V_{DD} < V_{DD\_MIN}$ ),  $V_{DDSDMMC}$  should be always lower than  $V_{DD}$
  - The  $V_{DDSDMMC}$  rising and falling time rate specifications must be respected (see Table 20 and Table 21)
  - In operating mode phase,  $V_{DDSDMMC}$  could be lower or higher than  $V_{DD}$ : All associated GPIOs powered by  $V_{DDSDMMC}$  are operating between  $V_{DDSDMMC\_MIN}$  and  $V_{DDSDMMC\_MAX}$ .
- $V_{DDUSB}$  can be connected either to  $V_{DD}$  or an external independent power supply (3.0 to 3.6V) for USB transceivers (refer to Figure 4 and Figure 5). For example, when the device is powered at 1.8V, an independent power supply 3.3V can be connected to  $V_{DDUSB}$ . When the  $V_{DDUSB}$  is connected to a separated power supply, it is independent from  $V_{DD}$  or  $V_{DDA}$  but it must be the last supply to be provided and the first to

**Figure 9. Startup in regulator OFF: slow  $V_{DD}$  slope - power-down reset risen after  $V_{CAP\_1}, V_{CAP\_2}$  stabilization**



1. This figure is valid whatever the internal reset mode (ON or OFF).

**Figure 10. Startup in regulator OFF mode: fast  $V_{DD}$  slope - power-down reset risen before  $V_{CAP\_1}, V_{CAP\_2}$  stabilization**



1. This figure is valid whatever the internal reset mode (ON or OFF).

The RTC clock sources can be:

- A 32.768 kHz external crystal (LSE)
- An external resonator or oscillator(LSE)
- The internal low power RC oscillator (LSI, with typical frequency of 32 kHz)
- The high-speed external clock (HSE) divided by 32

The RTC is functional in V<sub>BAT</sub> mode and in all low-power modes when it is clocked by the LSE. When clocked by the LSI, the RTC is not functional in V<sub>BAT</sub> mode, but is functional in all low-power modes.

All RTC events (Alarm, WakeUp Timer, Timestamp or Tamper) can generate an interrupt and wakeup the device from the low-power modes.

## 2.21 Low-power modes

The devices support three low-power modes to achieve the best compromise between low power consumption, short startup time and available wakeup sources:

- **Sleep mode**

In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs.

- **Stop mode**

The Stop mode achieves the lowest power consumption while retaining the contents of SRAM and registers. All clocks in the 1.2 V domain are stopped, the PLL, the HSI RC and the HSE crystal oscillators are disabled.

The voltage regulator can be put either in main regulator mode (MR) or in low-power mode (LPR). Both modes can be configured as follows (see [Table 5: Voltage regulator modes in stop mode](#)):

- Normal mode (default mode when MR or LPR is enabled)
- Under-drive mode.

The device can be woken up from the Stop mode by any of the EXTI line (the EXTI line source can be one of the 16 external lines, the PVD output, the RTC alarm / wakeup / tamper / time stamp events, the USB OTG FS/HS wakeup or the Ethernet wakeup and LPTIM1 asynchronous interrupt).

**Table 5. Voltage regulator modes in stop mode**

Voltage regulator configuration	Main regulator (MR)	Low-power regulator (LPR)
Normal mode	MR ON	LPR ON
Under-drive mode	MR in under-drive mode	LPR in under-drive mode

- **Standby mode**

The Standby mode is used to achieve the lowest power consumption. The internal voltage regulator is switched off so that the entire 1.2 V domain is powered off. The PLL, the HSI RC and the HSE crystal oscillators are also switched off. After entering

- Software configurable to OTG1.3 and OTG2.0 modes of operation
- USB 2.0 LPM (Link Power Management) support
- Battery Charging Specification Revision 1.2 support
- Internal FS OTG PHY support
- External HS or HS OTG operation supporting ULPI in SDR mode. The OTG PHY is connected to the microcontroller ULPI port through 12 signals. It can be clocked using the 60 MHz output.
- Internal USB DMA
- HNP/SNP/IP inside (no need for any external resistor)
- for OTG/Host modes, a power switch is needed in case bus-powered devices are connected

## 2.36 High-definition multimedia interface (HDMI) - consumer electronics control (CEC)

The devices embed a HDMI-CEC controller that provides hardware support for the Consumer Electronics Control (CEC) protocol (Supplement 1 to the HDMI standard).

This protocol provides high-level control functions between all audiovisual products in an environment. It is specified to operate at low speeds with minimum processing and memory overhead. It has a clock domain independent from the CPU clock, allowing the HDMI-CEC controller to wakeup the MCU from Stop mode on data reception.

## 2.37 Digital camera interface (DCMI)

The devices embed a camera interface that can connect with camera modules and CMOS sensors through an 8-bit to 14-bit parallel interface, to receive video data. The camera interface can sustain a data transfer rate up to 54 Mbytes/s in 8-bit mode at 54 MHz. It features:

- Programmable polarity for the input pixel clock and synchronization signals
- Parallel data communication can be 8-, 10-, 12- or 14-bit
- Supports 8-bit progressive video monochrome or raw bayer format, YCbCr 4:2:2 progressive video, RGB 565 progressive video or compressed data (like JPEG)
- Supports continuous mode or snapshot (a single frame) mode
- Capability to automatically crop the image

**Table 9. Legend/abbreviations used in the pinout table**

Name	Abbreviation	Definition
Pin name	Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type	S	Supply pin
	I	Input only pin
	I/O	Input / output pin
I/O structure	FT	5 V tolerant I/O
	TTa	3.3 V tolerant I/O directly connected to ADC
	B	Dedicated BOOT pin
	RST	Bidirectional reset pin with weak pull-up resistor
Notes	Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset	
Alternate functions	Functions selected through GPIOx_AFR registers	
Additional functions	Functions directly selected/enabled through peripheral registers	

**Table 10. STM32F777xx, STM32F778Ax and STM32F779xx pin and ball definitions**

Pin Number										Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
STM32F777xx					STM32F778Ax STM32F779xx										
LQFP100	LQFP144	UFBGA176	LQFP176	LQFP208	TFBGA216	WLCSP180 <sup>(1)</sup>	LQFP176	LQFP208	TFBGA216						
1	1	A2	1	1	A3	E10	1	1	A3	PE2	I/O	FT	-	TRACECLK, SPI4_SCK, SAI1_MCLK_A, QUADSPI_BK1_IO2, ETH_MII_TXD3, FMC_A23, EVENTOUT	-
2	2	A1	2	2	A2	F10	2	2	A2	PE3	I/O	FT	-	TRACED0, SAI1_SD_B, FMC_A19, EVENTOUT	-

Table 13. STM32F777xx, STM32F778Ax and STM32F779xx register boundary addresses<sup>(1)</sup> (continued)

Bus	Boundary address	Peripheral
	0x4000 8000- 0x4000 FFFF	Reserved
APB1	0x4000 7C00 - 0x4000 7FFF	UART8
	0x4000 7800 - 0x4000 7BFF	UART7
	0x4000 7400 - 0x4000 77FF	DAC
	0x4000 7000 - 0x4000 73FF	PWR
	0x4000 6C00 - 0x4000 6FFF	HDMI-CEC
	0x4000 6800 - 0x4000 6BFF	CAN2
	0x4000 6400 - 0x4000 67FF	CAN1
	0x4000 6000 - 0x4000 63FF	I2C4
	0x4000 5C00 - 0x4000 5FFF	I2C3
	0x4000 5800 - 0x4000 5BFF	I2C2
	0x4000 5400 - 0x4000 57FF	I2C1
	0x4000 5000 - 0x4000 53FF	UART5
	0x4000 4C00 - 0x4000 4FFF	UART4
	0x4000 4800 - 0x4000 4BFF	USART3
	0x4000 4400 - 0x4000 47FF	USART2
	0x4000 4000 - 0x4000 43FF	SPDIFRX
	0x4000 3C00 - 0x4000 3FFF	SPI3 / I2S3
	0x4000 3800 - 0x4000 3BFF	SPI2 / I2S2
	0x4000 3400 - 0x4000 37FF	CAN3
	0x4000 3000 - 0x4000 33FF	IWDG
	0x4000 2C00 - 0x4000 2FFF	WWDG
	0x4000 2800 - 0x4000 2BFF	RTC & BKP Registers
	0x4000 2400 - 0x4000 27FF	LPTIM1
	0x4000 2000 - 0x4000 23FF	TIM14
	0x4000 1C00 - 0x4000 1FFF	TIM13
	0x4000 1800 - 0x4000 1BFF	TIM12
	0x4000 1400 - 0x4000 17FF	TIM7
	0x4000 1000 - 0x4000 13FF	TIM6
0x4000 0C00 - 0x4000 0FFF	TIM5	
0x4000 0800 - 0x4000 0BFF	TIM4	
0x4000 0400 - 0x4000 07FF	TIM3	
0x4000 0000 - 0x4000 03FF	TIM2	

1. The gray color is used for reserved Flash memory addresses.

## 5 Electrical characteristics

### 5.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to  $V_{SS}$ .

#### 5.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at  $T_A = 25\text{ }^\circ\text{C}$  and  $T_A = T_{Amax}$  (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation ( $\text{mean} \pm 3\sigma$ ).

#### 5.1.2 Typical values

Unless otherwise specified, typical data are based on  $T_A = 25\text{ }^\circ\text{C}$ ,  $V_{DD} = 3.3\text{ V}$  (for the  $1.7\text{ V} \leq V_{DD} \leq 3.6\text{ V}$  voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated ( $\text{mean} \pm 2\sigma$ ).

#### 5.1.3 Typical curves

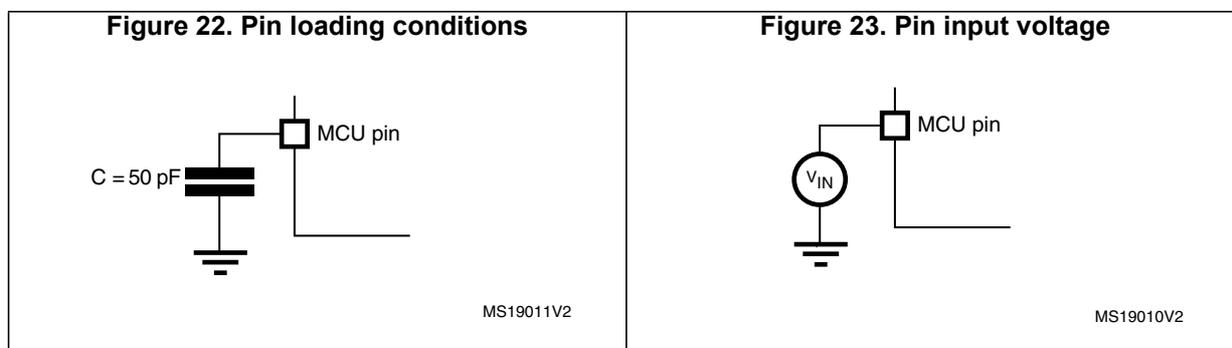
Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

#### 5.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in [Figure 22](#).

#### 5.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 23](#).



## 5.3 Operating conditions

### 5.3.1 General operating conditions

Table 17. General operating conditions

Symbol	Parameter	Conditions <sup>(1)</sup>	Min	Typ	Max	Unit	
f <sub>HCLK</sub>	Internal AHB clock frequency	Power Scale 3 (VOS[1:0] bits in PWR_CR register = 0x01), Regulator ON, over-drive OFF	0	-	144	MHz	
		Power Scale 2 (VOS[1:0] bits in PWR_CR register = 0x10), Regulator ON	Over-drive OFF	0	-		168
			Over-drive ON		-		180
		Power Scale 1 (VOS[1:0] bits in PWR_CR register= 0x11), Regulator ON	Over-drive OFF	0	-		180
Over-drive ON	-		216 <sup>(2)</sup>				
f <sub>PCLK1</sub>	Internal APB1 clock frequency	Over-drive OFF	0	-	45		
		Over-drive ON	0	-	54		
f <sub>PCLK2</sub>	Internal APB2 clock frequency	Over-drive OFF	0	-	90		
		Over-drive ON	0	-	108		
V <sub>DD</sub>	Standard operating voltage	-	1.7 <sup>(3)</sup>	-	3.6	V	
V <sub>DDA</sub> <sup>(4)(5)</sup>	Analog operating voltage (ADC limited to 1.2 M samples)	Must be the same potential as V <sub>DD</sub> <sup>(6)</sup>	1.7 <sup>(3)</sup>	-	2.4		
	Analog operating voltage (ADC limited to 2.4 M samples)		2.4	-	3.6		
V <sub>DDUSB</sub>	USB supply voltage (supply voltage for PA11,PA12, PB14 and PB15 pins)	USB not used	1.7	3.3	3.6		
		USB used	3.0	-	3.6		
V <sub>BAT</sub>	Backup operating voltage	-	1.65	-	3.6		
V <sub>DDSDMMC</sub>	SDMMC2 supply voltage (supply voltage for PG[12:9] and PD6 pins)	It can be different from V <sub>DD</sub>	1.7	-	3.6		
V <sub>DDDSI</sub>	DSI system operating	-	1.7	-	3.6		

**Table 39. Peripheral current consumption (continued)**

Peripheral		I <sub>DD</sub> (Typ) <sup>(1)</sup>			Unit
		Scale 1	Scale 2	Scale 3	
APB1 (up to 54 MHz)	TIM2	19.1	18.7	14.7	μA/MHz
	TIM3	14.6	14.0	10.6	
	TIM4	15.4	14.7	11.4	
	TIM5	18.1	17.6	13.6	
	TIM6	3.1	2.7	1.4	
	TIM7	3.0	2.7	1.1	
	TIM12	8.1	7.8	5.6	
	TIM13	5.4	5.1	3.1	
	TIM14	5.6	5.3	3.3	
	LPTIM1	9.8	9.6	6.9	
	WWDG	1.9	1.6	1.4	
	SPI2/I2S2 <sup>(3)</sup>	3.0	2.9	1.4	
	SPI3/I2S3 <sup>(3)</sup>	3.0	3.3	1.4	
	SPDIFRX	2.4	2.0	1.7	
	USART2	12.6	12.7	9.2	
	USART3	12.4	12.4	9.4	
	UART4	10.7	10.9	8.1	
	UART5	10.7	10.7	8.1	
	I2C1	8.9	8.9	6.4	
	I2C2	8.3	8.2	6.1	
	I2C3	8.1	8.2	6.1	
	I2C4	8.0	8.2	5.8	
	CAN1	6.3	6.4	4.4	
	CAN2	5.7	5.8	3.9	
	CAN3	7.4	7.1	5.6	
	HDMI-CEC	2.2	1.8	1.4	
	PWR	1.3	0.9	0.8	
	DAC <sup>(4)</sup>	4.8	4.2	3.6	
UART7	10.4	10.4	7.8		
UART8	11.1	11.3	8.3		

### 5.3.10 Internal clock source characteristics

The parameters given in [Table 45](#) and [Table 46](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 17](#).

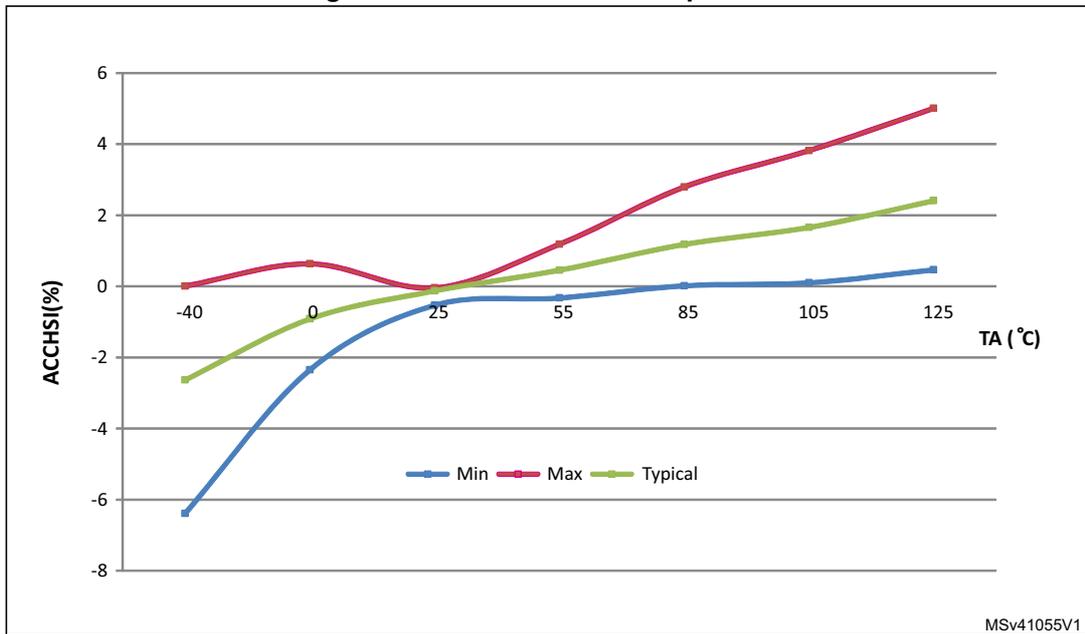
#### High-speed internal (HSI) RC oscillator

**Table 45. HSI oscillator characteristics (1)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{HSI}$	Frequency	-	-	16	-	MHz
$ACC_{HSI}$	HSI user trimming step <sup>(2)</sup>	-	-	-	1	%
	Accuracy of the HSI oscillator	$T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}^{(3)}$	- 8	-	4.5	%
		$T_A = -10 \text{ to } 85 \text{ }^\circ\text{C}^{(3)}$	- 4	-	4	%
		$T_A = 25 \text{ }^\circ\text{C}^{(4)}$	- 1	-	1	%
$t_{su(HSI)}^{(2)}$	HSI oscillator startup time	-	-	2.2	4	$\mu\text{s}$
$I_{DD(HSI)}^{(2)}$	HSI oscillator power consumption	-	-	60	80	$\mu\text{A}$

- $V_{DD} = 3.3 \text{ V}$ ,  $T_A = -40 \text{ to } 105 \text{ }^\circ\text{C}$  unless otherwise specified.
- Guaranteed by design.
- Guaranteed by characterization results.
- Factory calibrated, parts not soldered.

**Figure 32. ACCHSI versus temperature**



- Guaranteed by characterization results.

**Table 48. PLLI2S characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
f <sub>PLLI2S_IN</sub>	PLLI2S input clock <sup>(1)</sup>	-	0.95 <sup>(2)</sup>	1	2.10	MHz	
f <sub>PLLI2SP_OUT</sub>	PLLI2S multiplier output clock for SPDIFRX	-	-	-	216		
f <sub>PLLI2SQ_OUT</sub>	PLLI2S multiplier output clock for SAI	-	-	-	216		
f <sub>PLLI2SR_OUT</sub>	PLLI2S multiplier output clock for I2S	-	-	-	216		
f <sub>VCO_OUT</sub>	PLLI2S VCO output	-	100	-	432		
t <sub>LOCK</sub>	PLLI2S lock time	VCO freq = 192 MHz	75	-	200	µs	
		VCO freq = 432 MHz	100	-	300		
Jitter <sup>(3)</sup>	Master I2S clock jitter	Cycle to cycle at 12.288 MHz on 48KHz period, N=432, R=5	RMS	-	90	-	ps
			peak to peak	-	±280	-	
			Average frequency of 12.288 MHz N = 432, R = 5 on 1000 samples	-	90	-	ps
	WS I2S clock jitter	Cycle to cycle at 48 KHz on 1000 samples	-	400	-	ps	
I <sub>DD(PLLI2S)</sub> <sup>(4)</sup>	PLLI2S power consumption on V <sub>DD</sub>	VCO freq = 192 MHz	0.15	-	0.40	mA	
		VCO freq = 432 MHz	0.45	-	0.75		
I <sub>DDA(PLLI2S)</sub> <sup>(4)</sup>	PLLI2S power consumption on V <sub>DDA</sub>	VCO freq = 192 MHz	0.30	-	0.40	mA	
		VCO freq = 432 MHz	0.55	-	0.85		

1. Take care of using the appropriate division factor M to have the specified PLL input clock values.
2. Guaranteed by design.
3. Value given with main PLL running.
4. Guaranteed by characterization results.

**Table 49. PLLISAI characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f <sub>PLLSAI_IN</sub>	PLLSAI input clock <sup>(1)</sup>	-	0.95 <sup>(2)</sup>	1	2.10	MHz
f <sub>PLLSAIP_OUT</sub>	PLLSAI multiplier output clock for 48 MHz	-	-	48	75	
f <sub>PLLSAIQ_OUT</sub>	PLLSAI multiplier output clock for SAI	-	-	-	216	
f <sub>PLLSAIR_OUT</sub>	PLLSAI multiplier output clock for LCD-TFT	-	-	-	216	
f <sub>VCO_OUT</sub>	PLLSAI VCO output	-	100	-	432	

If  $f_{PLL\_IN} = 1$  MHz, and  $f_{MOD} = 1$  kHz, the modulation depth (MODEPER) is given by equation 1:

$$MODEPER = \text{round}[10^6 / (4 \times 10^3)] = 250$$

Equation 2

Equation 2 allows to calculate the increment step (INCSTEP):

$$INCSTEP = \text{round}[(2^{15} - 1) \times md \times PLLN / (100 \times 5 \times MODEPER)]$$

$f_{VCO\_OUT}$  must be expressed in MHz.

With a modulation depth (md) =  $\pm 2\%$  (4 % peak to peak), and PLLN = 240 (in MHz):

$$INCSTEP = \text{round}[(2^{15} - 1) \times 2 \times 240 / (100 \times 5 \times 250)] = 126md(\text{quantitized})\%$$

An amplitude quantization error may be generated because the linear modulation profile is obtained by taking the quantized values (rounded to the nearest integer) of MODPER and INCSTEP. As a result, the achieved modulation depth is quantized. The percentage quantized modulation depth is given by the following formula:

$$md_{\text{quantized}}\% = (MODEPER \times INCSTEP \times 100 \times 5) / ((2^{15} - 1) \times PLLN)$$

As a result:

$$md_{\text{quantized}}\% = (250 \times 126 \times 100 \times 5) / ((2^{15} - 1) \times 240) = 2.002\%(\text{peak})$$

Figure 34 and Figure 35 show the main PLL output clock waveforms in center spread and down spread modes, where:

- F0 is  $f_{PLL\_OUT}$  nominal.
- $T_{\text{mode}}$  is the modulation period.
- md is the modulation depth.

Figure 34. PLL output clock waveforms in center spread mode

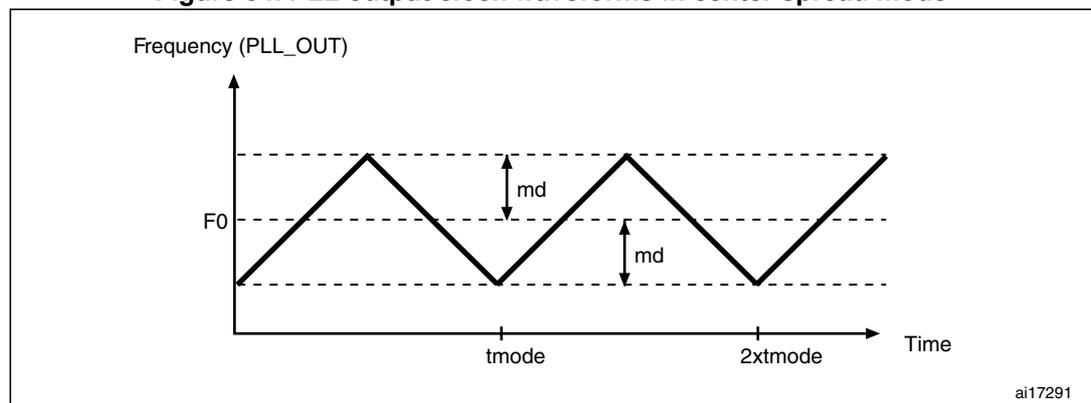


Table 71. ADC characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f <sub>TRIG</sub> <sup>(2)</sup>	External trigger frequency	f <sub>ADC</sub> = 30 MHz, 12-bit resolution	-	-	1764	kHz
		-	-	-	17	1/f <sub>ADC</sub>
V <sub>AIN</sub>	Conversion voltage range <sup>(3)</sup>	-	0 (V <sub>SSA</sub> or V <sub>REF</sub> - tied to ground)	-	V <sub>REF+</sub>	V
R <sub>AIN</sub> <sup>(2)</sup>	External input impedance	See <a href="#">Equation 1</a> for details	-	-	50	kΩ
R <sub>ADC</sub> <sup>(2)(4)</sup>	Sampling switch resistance	-	-	-	6	kΩ
C <sub>ADC</sub> <sup>(2)</sup>	Internal sample and hold capacitor	-	-	4	7	pF
t <sub>lat</sub> <sup>(2)</sup>	Injection trigger conversion latency	f <sub>ADC</sub> = 30 MHz	-	-	0.100	μs
		-	-	-	3 <sup>(5)</sup>	1/f <sub>ADC</sub>
t <sub>latr</sub> <sup>(2)</sup>	Regular trigger conversion latency	f <sub>ADC</sub> = 30 MHz	-	-	0.067	μs
		-	-	-	2 <sup>(5)</sup>	1/f <sub>ADC</sub>
t <sub>S</sub> <sup>(2)</sup>	Sampling time	f <sub>ADC</sub> = 30 MHz	0.100	-	16	μs
		-	3	-	480	1/f <sub>ADC</sub>
t <sub>STAB</sub> <sup>(2)</sup>	Power-up time	-	-	2	3	μs
t <sub>CONV</sub> <sup>(2)</sup>	Total conversion time (including sampling time)	f <sub>ADC</sub> = 30 MHz 12-bit resolution	0.50	-	16.40	μs
		f <sub>ADC</sub> = 30 MHz 10-bit resolution	0.43	-	16.34	μs
		f <sub>ADC</sub> = 30 MHz 8-bit resolution	0.37	-	16.27	μs
		f <sub>ADC</sub> = 30 MHz 6-bit resolution	0.30	-	16.20	μs
		9 to 492 (t <sub>S</sub> for sampling +n-bit resolution for successive approximation)				
f <sub>S</sub> <sup>(2)</sup>	Sampling rate (f <sub>ADC</sub> = 36 MHz, and t <sub>S</sub> = 3 ADC cycles)	12-bit resolution Single ADC	-	-	2.4	MspS
		12-bit resolution Interleave Dual ADC mode	-	-	4.5	MspS
		12-bit resolution Interleave Triple ADC mode	-	-	7.2	MspS

**Table 104. Asynchronous multiplexed PSRAM/NOR read timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$3T_{HCLK} - 1$	$3T_{HCLK} + 1$	ns
$t_{v(NOE\_NE)}$	FMC_NEx low to FMC_NOE low	$2T_{HCLK}$	$2T_{HCLK} + 0.5$	
$t_{tw(NOE)}$	FMC_NOE low time	$T_{HCLK} - 1$	$T_{HCLK} + 1$	
$t_{h(NE\_NOE)}$	FMC_NOE high to FMC_NE high hold time	0	-	
$t_{v(A\_NE)}$	FMC_NEx low to FMC_A valid	-	0.5	
$t_{v(NADV\_NE)}$	FMC_NEx low to FMC_NADV low	0	0.5	
$t_{w(NADV)}$	FMC_NADV low time	$T_{HCLK} - 0.5$	$T_{HCLK} + 1$	
$t_{h(AD\_NADV)}$	FMC_AD(address) valid hold time after FMC_NADV high	$T_{HCLK} + 0.5$	-	
$t_{h(A\_NOE)}$	Address hold time after FMC_NOE high	$T_{HCLK} - 0.5$	-	
$t_{h(BL\_NOE)}$	FMC_BL time after FMC_NOE high	0	-	
$t_{v(BL\_NE)}$	FMC_NEx low to FMC_BL valid	-	0.5	
$t_{su(Data\_NE)}$	Data to FMC_NEx high setup time	$T_{HCLK} - 1$	-	
$t_{su(Data\_NOE)}$	Data to FMC_NOE high setup time	$T_{HCLK} - 1$	-	
$t_{h(Data\_NE)}$	Data hold time after FMC_NEx high	0	-	
$t_{h(Data\_NOE)}$	Data hold time after FMC_NOE high	0	-	

1. Guaranteed by characterization results.

**Table 105. Asynchronous multiplexed PSRAM/NOR read-NWAIT timings<sup>(1)</sup>**

Symbol	Parameter	Min	Max	Unit
$t_{w(NE)}$	FMC_NE low time	$8T_{HCLK} - 1$	$8T_{HCLK} + 1$	ns
$t_{w(NOE)}$	FMC_NWE low time	$5T_{HCLK} - 1.5$	$5T_{HCLK} + 0.5$	
$t_{su(NWAIT\_NE)}$	FMC_NWAIT valid before FMC_NEx high	$5T_{HCLK} + 1.5$	-	
$t_{h(NE\_NWAIT)}$	FMC_NEx hold time after FMC_NWAIT invalid	$4T_{HCLK} + 1$	-	

1. Guaranteed by characterization results.

**Table 118. Quad-SPI characteristics (continued)in SDR mode<sup>(1)</sup> (continued)**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
tw(CKH)	Quad-SPI clock high and low time	-	t(CK)/2 - 1	-	t(CK)/2	ns
tw(CKL)			t(CK)/2	-	t(CK)/2 + 1	
ts(IN)	Data input setup time	-	0.5	-	-	
th(IN)	Data input hold time		3	-	-	
tv(OUT)	Data output valid time	2.7 V < V <sub>DD</sub> < 3.6 V	-	1.5	3.5	
		1.71 V < V <sub>DD</sub> < 3.6 V	-	1.5	2	
th(OUT)	Data output hold time	-	0.5	-	-	

1. Guaranteed by characterization results.

**Table 119. Quad SPI characteristics in DDR mode<sup>(1)</sup>**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Fck1/t(CK)	Quad-SPI clock frequency	2.7 V < V <sub>DD</sub> < 3.6 V CL=20 pF	-	-	80	MHz
		1.8 V < V <sub>DD</sub> < 3.6 V CL=15 pF	-	-	80	
		1.71 V < V <sub>DD</sub> < 3.6 V CL=10 pF	-	-	80	
tw(CKH)	Quad-SPI clock high and low time	-	t(CK)/2 - 1	-	t(CK)/2	ns
tw(CKL)			t(CK)/2	-	t(CK)/2 + 1	
ts(IN), tsf(IN)	Data input setup time	2.7 V < V <sub>DD</sub> < 3.6 V	0.75	-	-	
		1.71 V < V <sub>DD</sub> < 2 V	0.5	-	-	
thr(IN), thf(IN)	Data input hold time	2.7 V < V <sub>DD</sub> < 3.6 V	2	-	-	
		1.71 V < V <sub>DD</sub> < 2 V	3	-	-	
tvr(OUT), tvf(OUT)	Data output valid time	2.7 V < V <sub>DD</sub> < 3.6 V	-	8.5	10	
		1.71 V < V <sub>DD</sub> < 3.6 V DHHC=0	-	8	12	
		DHHC=1 Pres=1, 2...	-	T <sub>HCLK</sub> /2 + 1.5	T <sub>HCLK</sub> /2 + 2.5	
thr(OUT), thf(OUT)	Data output hold time	DHHC=0	7.5	-	-	
		DHHC=1 Pres=1, 2...	T <sub>HCLK</sub> /2 + 0.5	-	-	

1. Guaranteed by characterization results.

## Revision history

**Table 138. Document revision history**

Date	Revision	Changes
21-Mar-2016	1	Initial release.
26-Apr-2016	2	<p>DFSDM replaced by DFSDM1 in:</p> <ul style="list-style-type: none"> <li>– <i>Table 10: STM32F777xx, STM32F778Ax and STM32F779xx pin and ball definitions.</i></li> <li>– <i>Table 12: STM32F777xx, STM32F778Ax and STM32F779xx alternate function mapping .</i></li> <li>– <i>Table 13: STM32F777xx, STM32F778Ax and STM32F779xx register boundary addresses.</i></li> <li>– <i>Section 5.3.34: Digital filter for Sigma-Delta Modulators (DFSDM) characteristics.</i></li> </ul> <p>Updated <i>Table 2: STM32F777xx, STM32F778Ax and STM32F779xx features and peripheral counts</i> adding DFSDM1 features.</p> <p>Updated <i>Table 39: Peripheral current consumption</i> adding DFSDM1 current consumption.</p> <p>Updated cover in 2 pages.</p> <p>Updated cover replacing for SPI 'up to 50 Mbit/s' by 'up to 54 Mbit/s'.</p>
06-May-2016	3	<p>Updated <i>Table 2: STM32F777xx, STM32F778Ax and STM32F779xx features and peripheral counts</i> GPIO number.</p> <p>Updated <i>Table 12: STM32F777xx, STM32F778Ax and STM32F779xx alternate function mapping</i> adding CAN3_RX alternate function on PA8/AF11.</p>
22-Dec-2016	4	<p>Updated <i>Table 97: Dynamics characteristics: Ethernet MAC signals for RMII.</i></p> <p>Updated <i>Table 71: ADC characteristics</i> sampling rate.</p> <p>Updated all the notes removing 'not tested in production'.</p> <p>Updated <i>Figure 46: SPI timing diagram - slave mode and CPHA = 0</i> and <i>Figure 47: SPI timing diagram - slave mode and CPHA = 1(1)</i> with modified NSS timing waveforms (among other changes).</p> <p>Updated <i>Table 121: LTDC characteristics</i> clock output frequency at 65 MHz.</p> <p>Updated <i>Section 5.2: Absolute maximum ratings.</i></p> <p>Updated <i>Section 6: Package information</i> adding information about other optional marking or inset/upset marks.</p>